Digital Solution from R&D to Production
EVA100 MEASUREMENT SYSTEM

SINGLE SYSTEM COVERING R&D EVALUATION TO MASS PRODUCTION

Get your new devices to market faster with the EVA100 Digital Solution

- Compact, portable system with fully integrated digital IC testing capabilities
- Highly accurate timing synchronization and reliability boost evaluation efficiency
- Intuitive software interface does not require any specific skill set to operate the EVA100
- Total solution from R&D to production for better facility-wide communication
Getting to market quickly and reducing test costs are key requirements for consumer MCUs, IoT devices and SiPs, even high-mix products. The EVA100 Digital Solution is designed to meet customers’ demands.

- **Portable system for digital IC evaluation**
  - 40% smaller than the initial EVA100 measurement system
  - Integrates all needed measurement functions
  - Standard software covers evaluation needs
  - Able to hook and synchronize operations with external instruments

- **Expandable system covers a wide range of applications**
  - Supports mixed-signal device testing

**Target Devices**
- IoT devices, MCUs
- DFT/BIST-driven devices
- Small FPGA/ASICs, fingerprint ICs, touch controllers
- SiP/module devices

**Purpose**
- R&D evaluation
- Wafer sort, package test, DFT testing
- Package validation, IP validation, failure analysis
- System level test

- **Intuitive operation improves debugging efficiency**
  - No specific skill required to start using the EVA100
  - Quick and easy operation with GUI tools
  - Create test sequences by using templates

- **Scalable design for easy expansion**
  - Easily follow changes in production volume

**Feature**

**System module**
- System bus control and synchronization
- Utility power supply
- Control of relays, I2C bus, external instrument control

**Digital with analog, power supply function**
- Digital I/O 256 ch/testing unit, 100-Mbps base rate
- Free-run clock feature with double clock mode
- 128-MW pattern memory, scan pattern
- Fail capture memory, digital capture memory
- High-voltage pin, per-pin PMU, TMU
- 18-bit AWG/DGT, VRef
- Device power supply 500 mA x N (gangable)
- Secondary device power supply (PDPS)

**Software (Measurement Atelier)**
- Pattern editor, logic analyzer tool
- Shmoo tool
- Report generator (automated report generating)
- Sequence gadget (test templates)
- Debug and evaluation tools

**Specification**

**Size (testing unit)**
- (W) 220 mm x (H) 206 mm x (D) 472 mm

**Software (Measurement Atelier)**
- Engineering model: 128 ch
- Production model: 256 ch, 512 ch, 768 ch, 1,024 ch

---

ADVANTEST CORPORATION
www.advantest.com

EVA Project  E-mail:info_eva@advantest.com

© 2017 ADVANTEST CORPORATION